# ICCHIBAN 2 & 4 & 6: NRPB Results

Luke Hager, David Bartlett and Rick Tanner National Radiological Protection Board, UK



#### Standard issue neutron dosemeters of simple design, processed using simple techniques developed for personal dosimetry, may be used to estimate the neutron component in spacecraft.

- Electrochemically etched pits in poly allyl diglycol carbonate (PADC or CR-39<sup>®</sup>) etched track detectors are identified and counted using fully automated read-out procedures.
- ICCHIBAN irradiations have allowed determination of the LET threshold of detection for the dosemeter and etch regime.



## **Dosemeter Layout for Irradiation**



# **Processing Methods**

Electrochemical etch - back face

- 11.5 hours 20% NaOH at 40°C followed contiguously
- by 8 hours 20% NaOH at 40°C at 23.5 kVcm<sup>-1</sup>

# Subsequent Chemical etch - both faces

• 18 hours 20% NaOH at 80°C



## Comparison of Etch methods





<sup>56</sup>Fe 60° to normal incidence

# NASA STS 105 - obvious HZE track



#### Back face



# NASA STS 105 - typical HZE track



#### Back face

Front face

# • PADC neutron personal dosemeter responds to neutrons plus neutron-like interactions of high-energy protons

- Only responds directly to protons of  $E_p$  < about 1 MeV
- Some response to heavier charged particles with LET<sub>200</sub> > about 30 keV  $\mu$ m<sup>-1</sup>, depending on particle type
- Can distinguish HZE electrochemically etched tracks by second chemical etch
- Preliminary measurements on NASA STS and ISS indicate that a correction of 20 to 30% is necessary to account for the detector HZE response.

# **ICCHIBAN-2** Irradiations

# Angle dependence of response ICCHIBAN-2 data

HIMAC Japan 2002 1.2 <sup>56</sup>Fe 1.0 <sup>28</sup>S; **Electrochemical Etch** <sup>12</sup>C Tracks per particle 0.8 0.6 0.4 0.2 0.0 15 0 30 45 60 75

Angle, degrees from normal incidence

# Angle dependence of relative response: ICCHIBAN-2 data

	00	15°	300	60°	75°	ISO free air	ISO on body
<sup>56</sup> Fe 464 MeV/n	0.90	0.85	0.70	0.30	0	30% to 40%	15% to 20%
<sup>28</sup> Si 469 MeV/n	0.50	0.55	0.02	0	0	about 5%	about 2%

As well as helping to improve the neutron dose assessment the ICCHIBAN calibrations are also very useful to help understand a little bit better the response to HZE of our detector Results of ICCHIBAN-4 Irradiations

#### Electrochemical etching- single detector charged particle results: <sup>12</sup>C 400 MeV/n

Particle/ Energy	Shielding condition	LET keV µm <sup>-1</sup>	Dose mGy	Fluence cm <sup>-2</sup>	Corrected Net Tracks <sup>(a)</sup> cm <sup>-2</sup>		Note
					Det.1	Det.2	
<sup>12</sup> C 400 MeV/n	zero	10.963		57000	8	1	(b)
	5 g cm <sup>-2</sup> Al	?		?	9	11	(c)
	10 g cm <sup>-2</sup> Al	?	1	?	21	14	(d)
	5 g cm <sup>-2</sup> PMMA	?		?	19	15	(e)

(a) Observed number of tracks cm  $^{\rm -2}$  after subtraction of background and corrected for non-linearity at high track density

(b) Not significantly different from background. Primary beam particles below LET threshold

(c), (d), (e) Primary beam particles below LET threshold. A few higher LET fragments? - some larger tracks

In subsequent figures, detector 1 is edged in orange, detector 2 in red.

## **Electrochemical etching- single detector**

#### charged particle results: <sup>20</sup>Ne 400 MeV/n

Particle/ Energy	Shielding condition	LET keV µm <sup>-1</sup>	Dose mGy	Fluence cm <sup>-2</sup>	Corrected Net Tracks <sup>(a)</sup> cm <sup>-2</sup>		Note
					Det.1	Det.2	
<sup>20</sup> Ne 400 MeV/n	zero	30.959		20200	690	23	(f)
	5 g cm <sup>-2</sup> Al	?:		?	225	1180	(g)
	10 g cm <sup>-2</sup> Al	?	1	?	8390	5520	(h)
	5 g cm <sup>-2</sup> PMMA	?		?	5000	7020	(i)

(f), (g) At LET threshold – some non-uniformity of response across/between detectors because of small differences in applied field strength during processing
(h), (i) Just on LET threshold – some non-uniformity of response

In subsequent figures, detector 1 is edged in orange, detector 2 in red

#### Electrochemical etchingsingle detector charged particle results: <sup>56</sup>Fe 500 MeV/n

Particle/ Energy	Shielding condition	LET keV µm <sup>-1</sup>	Dose mGy	Fluence cm <sup>-2</sup>	Corrected Net Tracks <sup>(a)</sup> cm <sup>-2</sup>		Note
					Det.1	Det.2	
<sup>56</sup> Fe 500 MeV/n	zero	~ 190		~3300	3980	3790	(j)
	5 g cm <sup>-2</sup> Al	?		?	3420	3440	(k)
	10 g cm <sup>-2</sup> Al	?	1	?	380	360	(I)
	5 g cm <sup>-2</sup> PMMA	?		?	3640	3570	(m)

(j), (k) Above threshold, 100% detection efficiency

- (I) Beyond Bragg peak- some fragments plus a few secondary neutrons?
- (m) Above threshold, 100% detection efficiency

In subsequent figures, detector 1 is edged in orange, detector 2 in red





#### 506 microns

#### 516 microns



#### 485 microns

#### 500 microns



# Results of ICCHIBAN-6 Irradiations

#### Electrochemical etching ICCHIBAN-6 charged particle results

Particle/ Energy	Shielding condition	LET keV µm⁻¹	Nominal Fluence cm <sup>-2</sup>	Corrected for sever Det.1	al net track al detecto Det.2	ks cm <sup>-2</sup> rs <u>Det.3</u>
<sup>12</sup> C 135 MeV/n	Bare Beam	21.2	5000	5	2	19
	PMMA absorber	?	5000	3691	3256	3017
<sup>40</sup> Ar 500 MeV/n	Bare Beam	89.3	5000	4489	4993	4858
	PMMA absorber	?	5000	2990	3053	3119
<sup>84</sup> Kr 400 MeV/n	Bare Beam	397	5000	3375	3337	3326
	PMMA absorber	?	5000	3135	3026	3176

## ICCHIBAN 6: <sup>12</sup>C 135 MeV/n through PMMA

![](_page_25_Picture_1.jpeg)

Detector 2 (511 µm)

Detector 3 (542 µm)

#### **ICCHIBAN-6** Blind # 5

![](_page_26_Picture_1.jpeg)

# SUMMARY

• Efficiency of detection of charged particles highly dependent on particle type, energy and angle of incidence - results in low isotropic response for the electrochemical etch method used

• For neutron dose assessment the HZE response of the detector is not a problem as long as it can be subtracted

• A subsequent chemical etch is performed which identifies HZE tracks and removes unwanted HZE component from neutron dose assessment

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